

Applicant: Nobuhiro Nunoya et al.

Confirmation No.: 4938

Serial No.: 10/527,355

Att'y Docket No.: 14321.67

Filing Date: March 7, 2005

Art Unit: 2811

For:

OPTICAL SEMICONDUCTOR DEVICE AND OPTICAL SEMICONDUCTOR
INTEGRATED CIRCUIT

THIRD SUPPLEMENTAL INFORMATION DISCLOSURE
CITATIONS MADE BY APPLICANT

U.S. Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Issue <u>Date</u>	<u>Name</u>
PS 1	6,320,888 B1	11/20/2001	Tanaka et al.
PS 2	6,530,698 B1	03/11/2003	Kuhara et al.

Foreign Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Publication <u>Date</u>	Country or <u>Patent Office</u>	<u>Translation</u>
PS 3	0 790 682 A1	08/20/1997	EP	N/A
PS 4	01-118806	05/11/1989	Japan	No
PS 5	62-202583	09/07/1987	Japan	No
PS 6	01-025586	01/27/1989	Japan	No

Other Documents
 (including author, title, pertinent pages, etc.)

Examiner
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PS 7 Abstract of Japanese Patent Publication No. 63-116485, published May 20, 1988.

 Examiner: /Patrick Stafford/ Date Considered: 01/05/2007

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SECOND SUPPLEMENTAL INFORMATION DISCLOSURE
CITATIONS MADE BY APPLICANT

U.S. Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Issue <u>Date</u>	Name
PS 1	5,022,042	06/04/1991	Bradley
PS 2	5,157,468	10/20/1992	Matsumoto
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Foreign Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Publication <u>Date</u>	Country or <u>Patent Office</u>	Translation
PS 4	55-123188	09/22/1980	Japan	No
PS 5	2000-223784	08/11/2000	Japan	No

Other Documents
 (including author, title, pertinent pages, etc.)

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- PS 1 T. Tanaka et al., *Hybrid Integrated External Cavity Laser without Temperature Dependent Mode Hopping*, Electronics Letters, Vol. 35, No. 2, January 21, 1999, pp. 149-150.
- PS 2 Takeshi Kurosaki et al., *A Method for Reduction in Internal Reflection of Monolithically Integrated Optical Devices with Butt-Jointed Optical Waveguides*, C-I, Vol. J79-C-I, No. 12, December 25, 1996, pp. 482-483 (with concise English translation).
- PS 3 Yoshiaki Nakano et al., *Analysis of DFB, and DBR Lasers Coupled to Fabry-Perot Resonator with Consideration on Their Temperature Compensation Properties*, Department of Electronic Engineering, University of Tokyo, July 24, 1985, pp. 55-56 (with concise English translation).
- PS 4 Toru Kusakawa, *Lens Optics*, Tokai University Press, December 25, 1998, pp. 273-288 (with concise English translation).

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U.S. Patent Documents

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PS 2	06-338650	12/06/1994	Japan	No
PS 3	02-074909	03/14/1990	Japan	No
PS 4	08-211342	08/20/1996	Japan	No
PS 5	09-036495	02/07/1997	Japan	No
PS 6	09-092924	04/04/1997	Japan	No
PS 7	09-331102	12/22/1997	Japan	No
PS 8	2000-019345	01/21/2000	Japan	No
PS 9	2000-223787	08/11/2000	Japan	No
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PS 11	2002-076513	03/15/2002	Japan	No
PS 12	2002-328244	11/15/2002	Japan	No

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PS 13 Kazuo Sakai et al., *1.5 μm Range InGaAsP/InP Distributed Feedback Lasers*, IEEE Journal of Quantum Electronics, Vol. QE-18, No. 8, August 1982, pp. 1272-1278.

PS 14 Hajime Asahi et al., *New III-V Compound Semiconductors TlInGaP for 0.9 μm to over 10 μm Wavelength Range Laser Diodes and Their First Successful Growth*, Jpn. J. Appl. Phys., Vol. 35, 1996, pp. L876-L879.

PS 15 K. Tada et al., *Temperature Compensated Coupled Cavity Diode Lasers*, Optical and Quantum Electronics, Vol. 16, 1984, pp. 463-469.

References Cited by Applicants

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

Examiners will consider all citations submitted in conformance with 37 C.F.R. § 1.98 and MPEP Sec. 609 and place their initials adjacent the citations in the spaces provided on this form. Examiners will also initial citations not in conformance with the guidelines which may have been considered. A reference may be considered by the Examiner for any reason whether or not the citation is in full conformance with the guidelines. A line will be drawn through a citation if it is not in conformance with the guidelines AND has not been considered. A copy of the submitted form, as reviewed by the Examiner, will be returned to the applicant with the next communication. The original of the form will be entered into the application file.

Each citation initialed by the Examiner will be printed on the issued patent in the same manner as references cited by the Examiner on Form PTO-892.

The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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